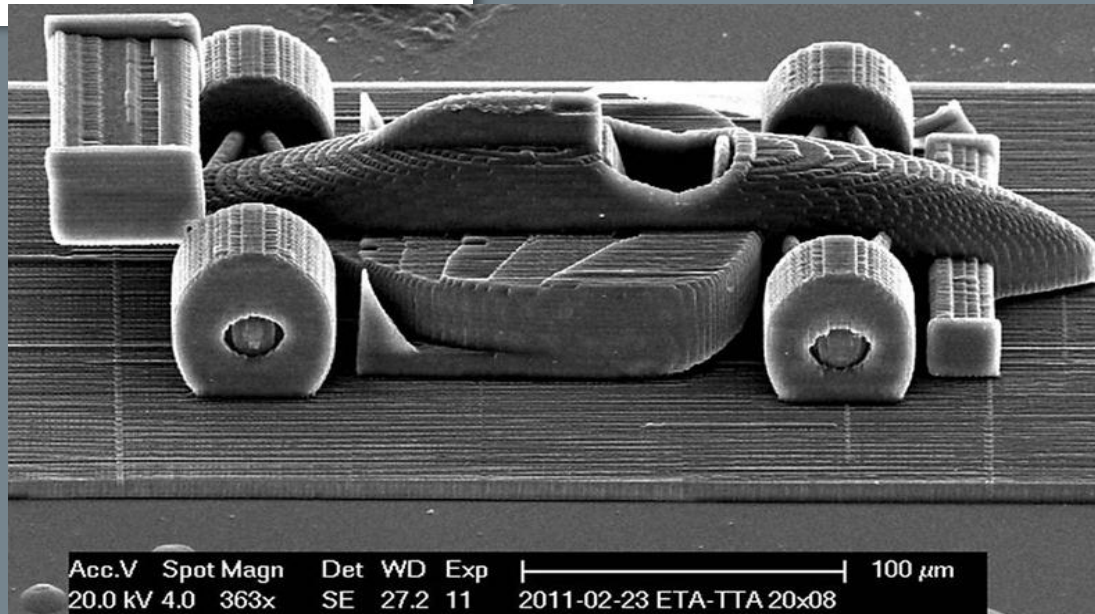




UNIVERSITY OF PATRAS

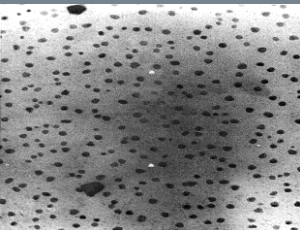
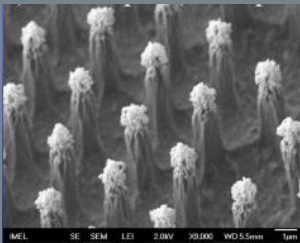
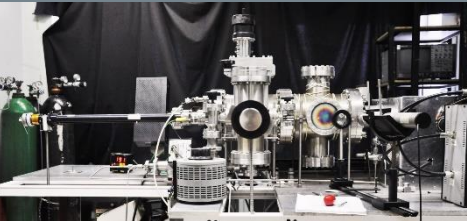
Department
Of Chemical
Engineering



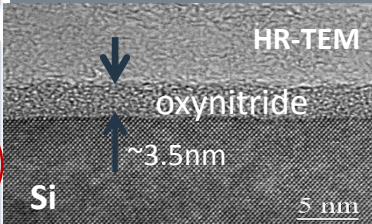
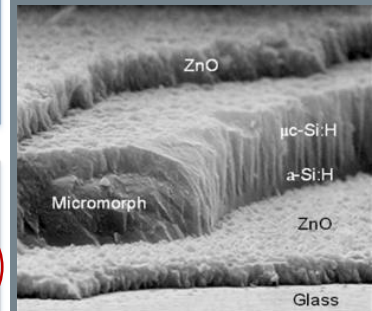
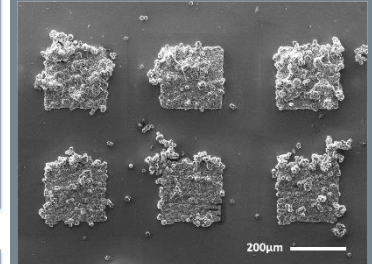
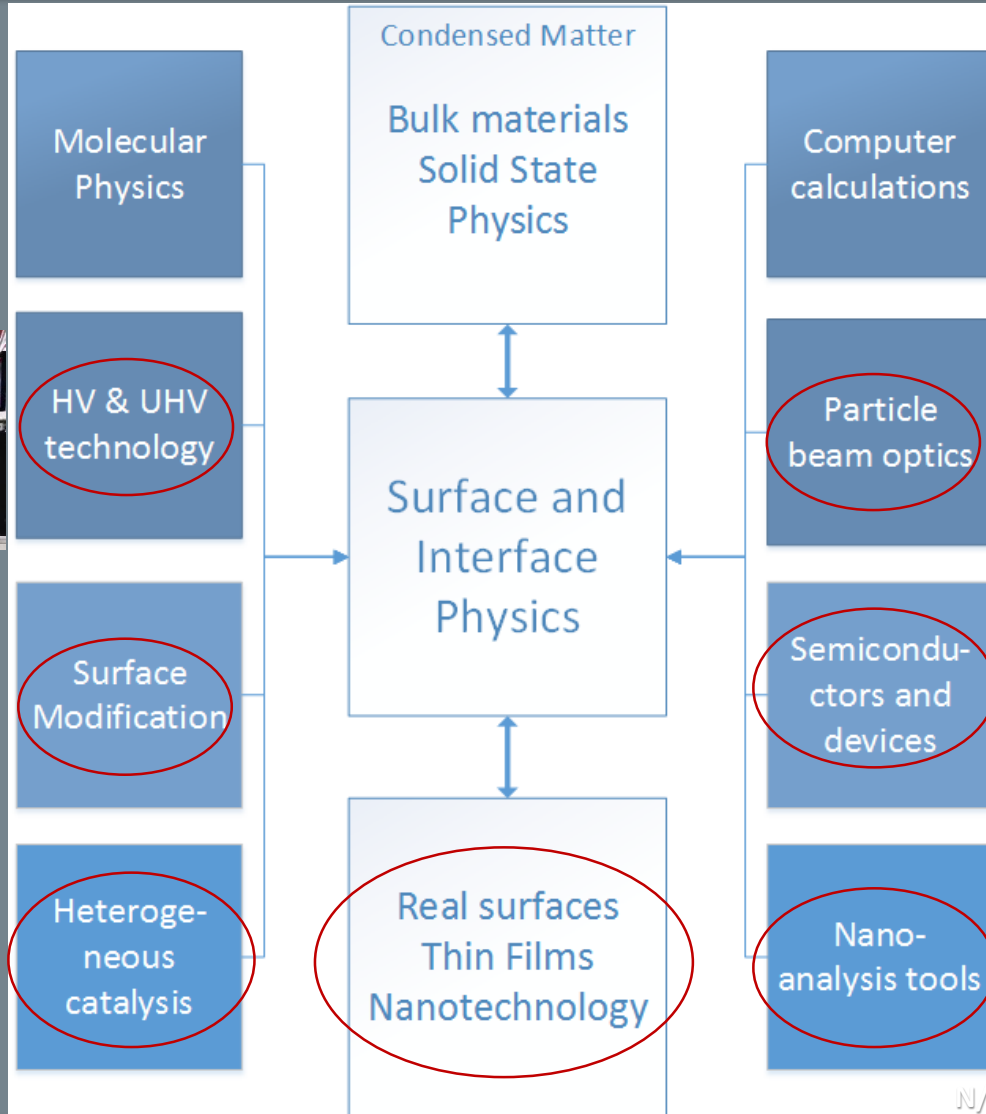
Surface, Interface and Thin Film Science and Technology

E. Amanatides, S. Kennou, D. Kouzoudis, S. Ladas, D. Mataras

General description of the Research Area



6nm Pd on α -Al₂O₃



Oxynitride properties by XPS:
N/Si ratio: 0.54 Thickness ~ 3.2 nm

PLASMA TECHNOLOGY LABORATORY

Prof. Dimitrios Mataras
PECVD of semiconductors,
surface modification



www.plasmatech.gr

Assist. Prof. E. Amanatides
PECVD, thin films
characterization

SURFACE SCIENCE LABORATORY

Prof. Stella Kennou
Experimental Surface
Physics



<http://athena4.chemeng.upatras.gr/>

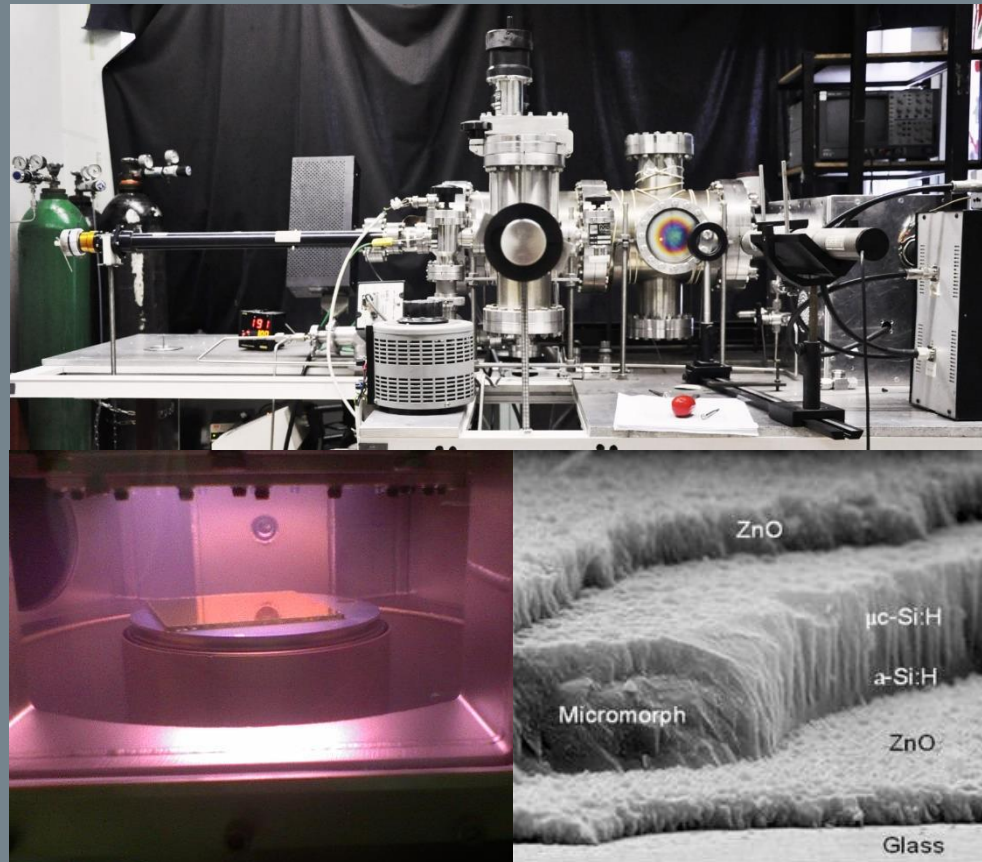
Prof. Spyros Ladas
Surface Science

ELECTRON BEAM LITHOGRAPHY LABORATORY

Assist. Prof. Dimitrios Kouzoudis
Magnetoelastic materials, sensors,
zeolites



<http://www.des.upatras.gr/physics/kouzoudis/ourgroup/home.htm>

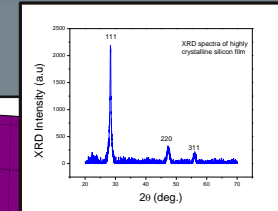
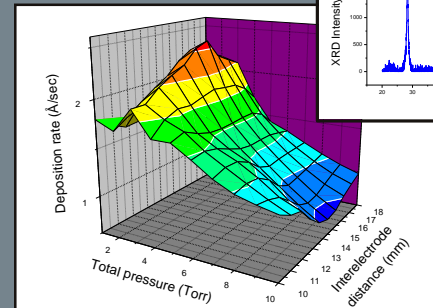


Plasma Technology Laboratory

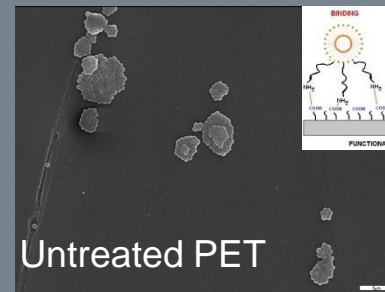
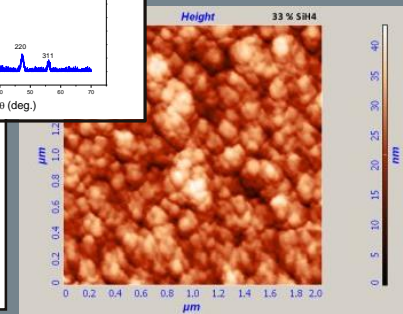
Plasma Enhanced Chemical Vapor Deposition of Thin Films and Surface Modification

- Plasma Enhanced Chemical Vapor Deposition of hydrogenated silicon for thin film photovoltaics. Increase of film growth rate and improve materials quality
- Atmospheric and low pressure plasma treatment and grafting of polymers and metals for antimicrobial surfaces and biomedical devices
- Thin Films and surfaces physicochemical characterization (SPM, XRD, Raman, IR and UV/Vis spectroscopies)

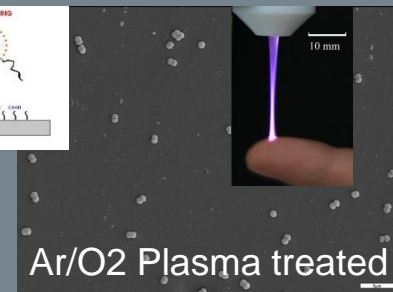
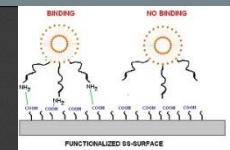
Silicon thin films growth rate



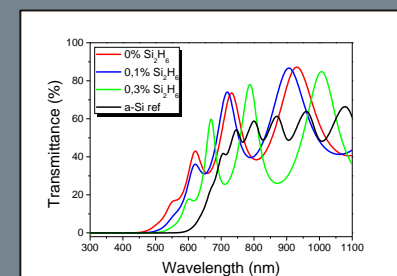
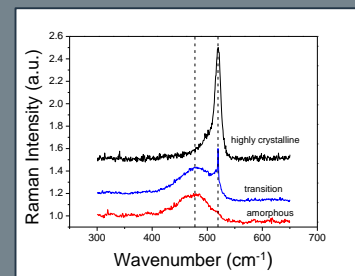
and structure



Untreated PET



Ar/O₂ Plasma treated



- 1 Professor, 1 Assistant Professor, 1 Lecturer, 5 PhD Student, 6 diploma thesis students



D. Mataras, Prof.



E. Amanatides
Assist. Prof



N. Spiliopoulos
Lect.(Physics Dept.)



E. Farsari, PhD
Thin Films
PECVD, AFM



V. Vrakatselli, PhD
Superhydrophilic Thin
Films, Surface
modification



P. Dimitrakellis, PhD
PECVD silicon
New Plasma
Sources



J. Alexiou, PhD
PECVD silicon
Optoelectronic
properties

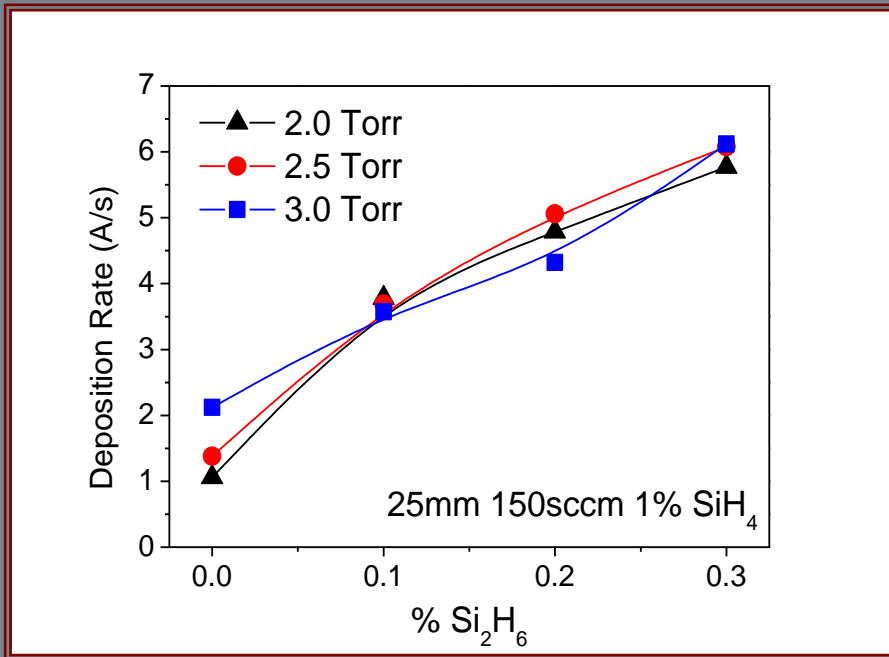


G. Tsigaras, PhD
Plasma Diagnostics
and modelling

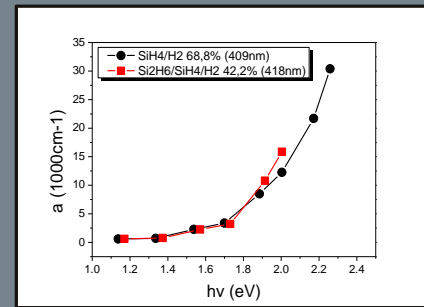
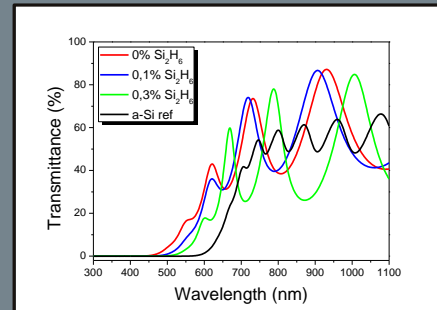
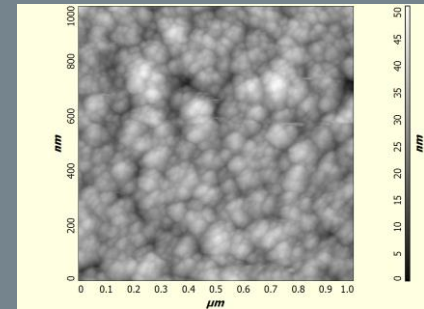
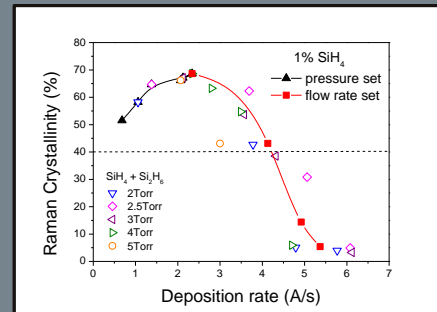
Research Activity: PECVD of Si:H thin films

Patent: Application No./Patent No. 12306522.9-1508, 2012 Title:

Microcrystalline Silicon Thin Film PECVD using hydrogen and Silane Mixtures,
 European Patent Office 5.12.12, V. Lahooon, A. Madec, E. Amanatides, D. Mataras,
 AIR LIQUIDE - UNIVERSITY OF PATRAS



Catalytic effect of small disilane addition on film growth rate of microcrystalline silicon thin films

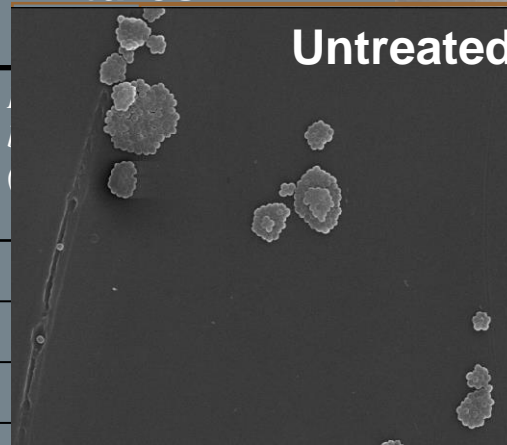


Materials quality is preserved even if the growth rate is 5 to 6 times higher!

Research Activity: Antimicrobial Surfaces

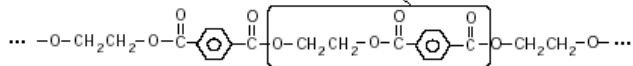
PET treatment from various O₂/He mixtures

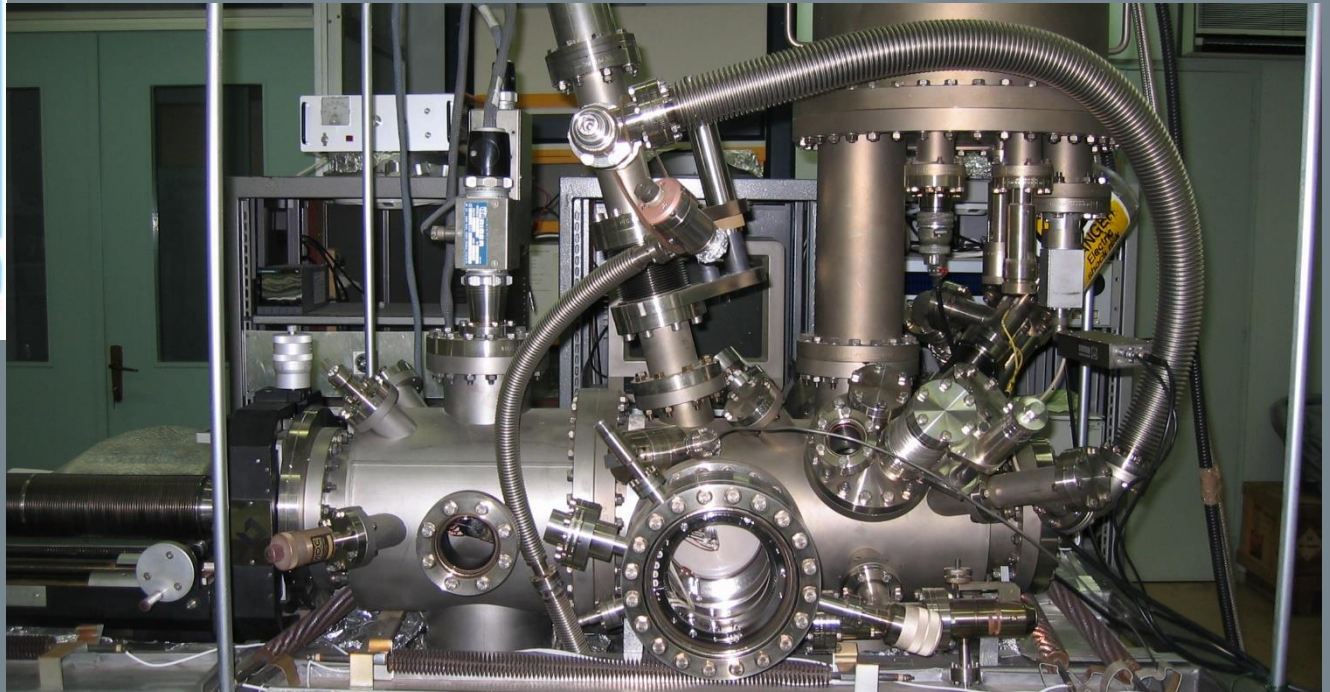
Sample name	He flow rate (sccm)	O ₂ flow rate (sccm)	Pressure (Torr)	RF voltage V _{RF} (Volt)		
PET5	20	0	0.25	305		
PET6	18	2	0.25	306		
PET7	16	4	0.25	278		
PET8	10	10	0.25	242	-30	1.2
PET9	0	20	0.25	200	-30	1.2
PET10	20	0	0.5	300	-30	2.0



Redeas of bacteria in high ison
with plasma treatment
with plasma treatment

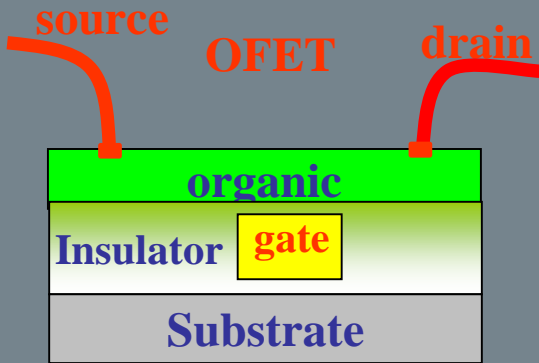
ethylene terephthalate monomer



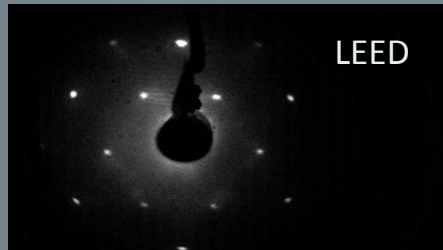
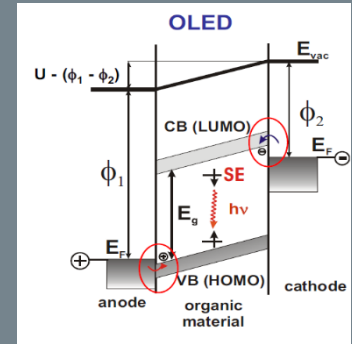


SURFACE SCIENCE LABORATORY

S. Kennou, S. Ladas



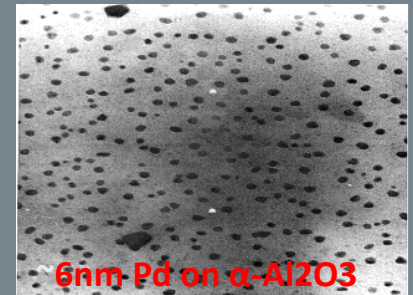
- Surface and Interface Studies of Electronic Materials
 - Material Interfaces for Organic Electronics
 - Metal-semiconductor and metal/ceramic Interfaces



LEED

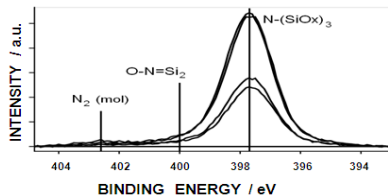
- Surface Science aspects of Heterogeneous Catalysis
 - Experiments on single-crystal model catalysts
 - Study of realistic model catalysts

$(\sqrt{3} \times \sqrt{3})R30^\circ \text{MgCl}_2/\text{Si}(111)$

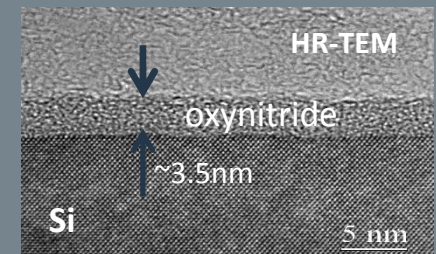


~6nm Pd on $\alpha\text{-Al}_2\text{O}_3$

OXYNITRIDE FILMS/Si : N1s XPS



- Ex-situ Spectroscopic Materials Characterization in the frame of :
 - Research collaborations both in Greece and abroad
 - ISO17025-Accredited Surface Analysis Services



Oxynitride properties by XPS:
N/Si ratio: 0.54 Thickness ~ 3.2 nm

- FACULTY MEMBERS (2):

Prof. Stella Kennou



Prof. Spyros Ladas



- GRADUATE STUDENTS (3):

Dimitris Tsikrintzis (Chemical Engineering)

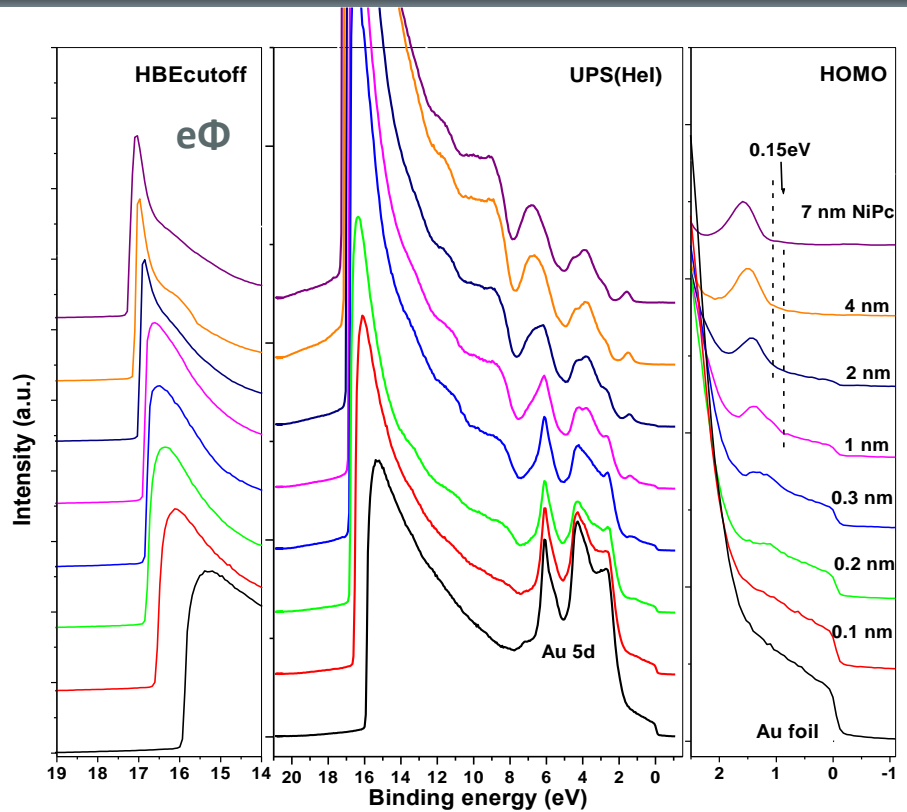
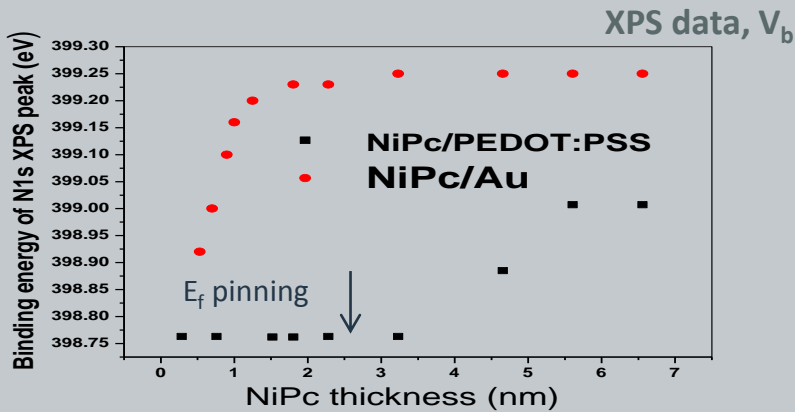
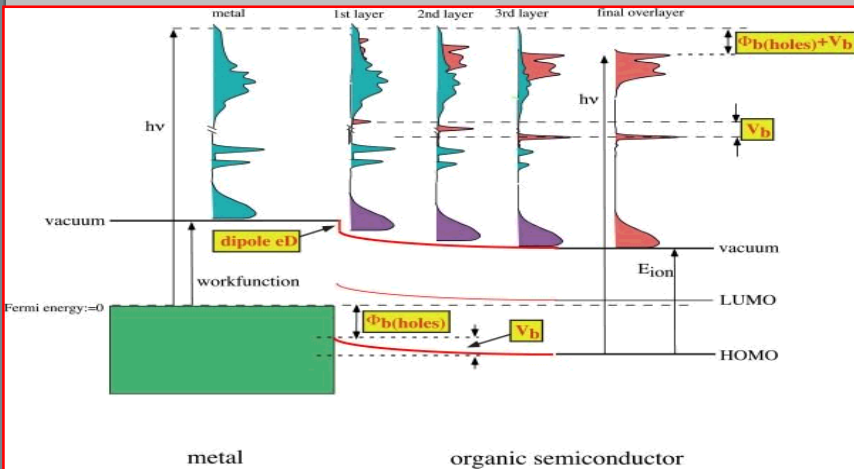
Giorgos Skoulatakis (Materials Science)

Kostas Emmanouil (Materials Science)

- At the moment, there are three (3) undergraduate students working towards their Diploma Thesis.

Material Interfaces for Organic Electronics Project Description

Growth of Ni-phthalocyanine films by thermal evaporation in UHV on Au, PEDOT:PSS, Ag and ITO substrates and XPS / UPS measurements during the evolution of the NiPc /substrate interface



Determination by XPS/UPS of :

Ionization Energy :

$$I = e\Phi + \text{HOMO}_{\text{cutoff}}$$

Band bending:

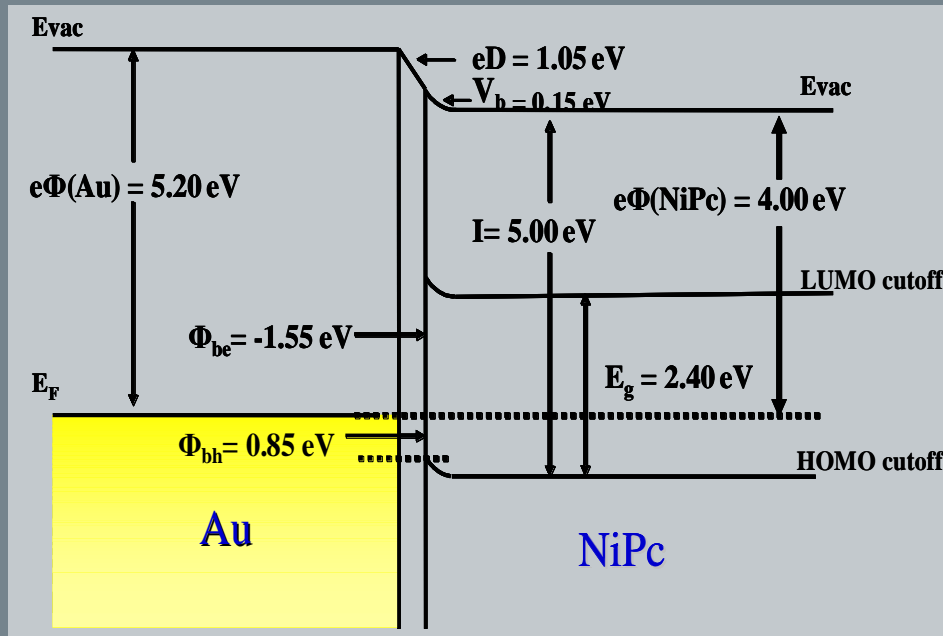
$$V_b$$

Interface dipole:

$$eD = \Delta e\Phi - V_b$$

Hole injection barrier :

$$\Phi_{bh} = \text{HOMO}_{\text{cut-off}} - V_b$$



(WF / eV)	eD (eV)	HOMO _{c.o} (eV)	Φ_{bh} (eV)
NiPc(4.0)			
Au (5.2)	-1.05	0.85	0.85
PEDOT:PSS (4.9)	-0.6	0.5	0.5
PEDOT:PSS (4.7)	-0.4	0.5	0.5
Ag (4.4)	-0.3	0.9	0.9
ITO (4.2)	-0.2	1.0	1.0

- The results demonstrate the influence of the substrate type and treatment (e.g. sputtered and not-sputtered PEDOT:PSS) on the various factors affecting device performance, the main one being the **Hole Injection Barrier** (last column). The lowest (most desirable) value is obtained on the PEDOT:PSS substrate for NiPc.

Spectroscopic Thin Film Characterization

/inadvertent "Carbon" contamination /

Material II

Material I

SUBSTRATE (e.g. Si wafer)

Interfaces

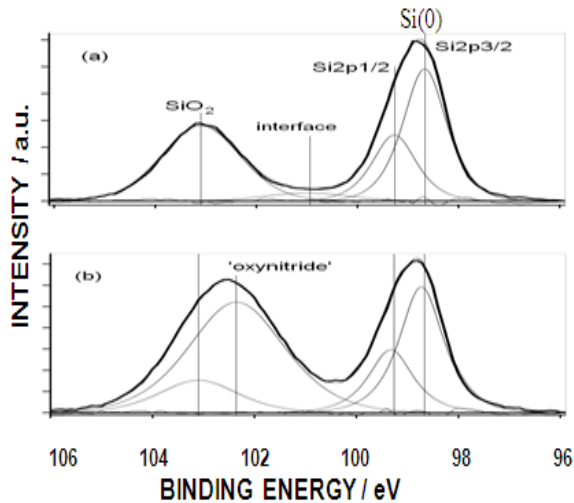
< 10 nm
(XPS-
visible)

Develop methods for exploiting spectroscopic data, to extract in a single measurement **composition and thickness** of individual films in stacks of interest for nano-electronics (e.g. high-k oxides) and nano-coatings (e.g. anti-corrosion layers on structural alloys)

CASE STUDY : XPS on plasma-nitrided SiO₂ films ; STACK : Si substrate / nitrided film / superficial 'C'
OBJECTIVE: Obtain thickness and nitrogen content of ultra-thin oxynitride film from XPS data

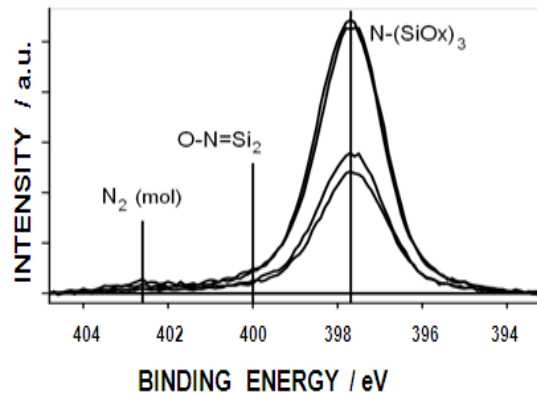
PEAKFITTING IN THE Si 2p REGION

(a) 2NM07 (plasma OFF) (b) 2NM05 (10 min plasma)



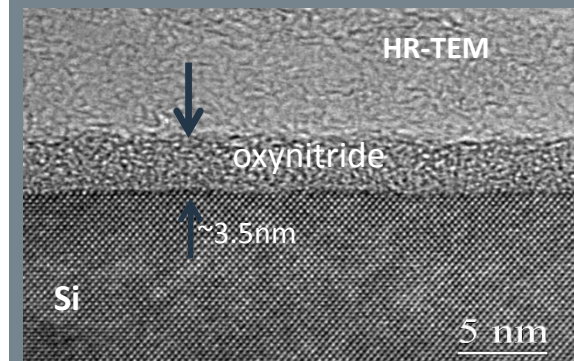
PHOTOPEAKS IN THE N 1s REGION

2NM03/45°, 2NM03/0°, 2NM05/45°, 2NM05/0° (in descending order)



For nitrided film (2NM05) :

- N/Si ratio: 0.54 (only by XPS)
- XPS-derived thickness ~ 3.2 nm (in excellent agreement with HR-TEM)



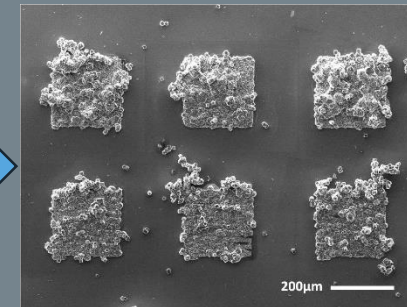
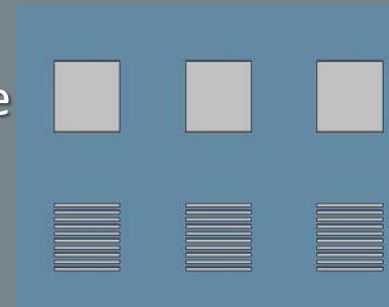
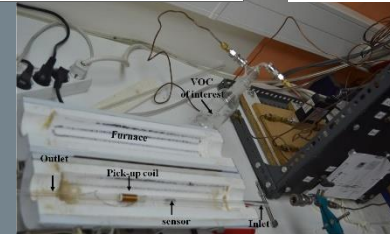
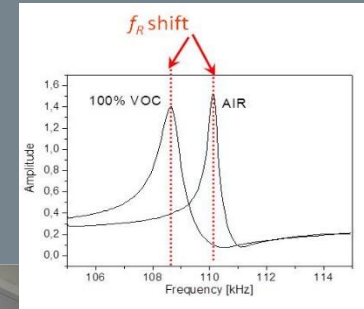
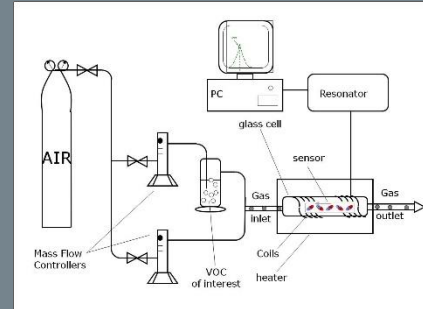


Electron Beam Lithography Lab

Magnetoelastic materials, sensors and zeolites

- Magnetoelastic sensors: Synthesis and characterization of zeolite films on magnetoelastic ribbons (Metglas)
 - sensors of VOC's and other gases
 - determine mechanical properties of zeolite films upon gas adsorption

- Electron beam lithographed microfilms
 - controlled size and position of zeolite films upon Metglas
 - Dimensions in the micro-scale
 - Integration to micro-devices
 - Enhanced sensing ability





Assist. Prof. Dimitrios Kouzoudis
Magnetoelastic materials, sensors, zeolites

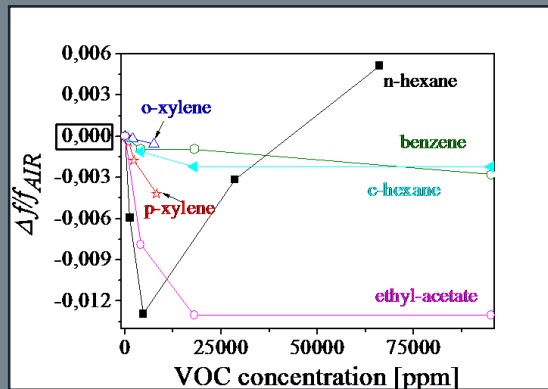


Theodore Baimpos, Chemical Engineer, PhD (sensors, zeolites, modelling)

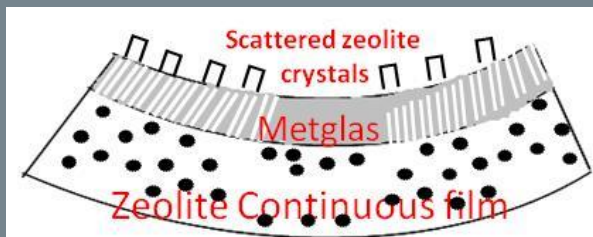


Vassiliki Tsukala, Chemical Engineer, PhD (zeolites, lithography, characterization techniques)

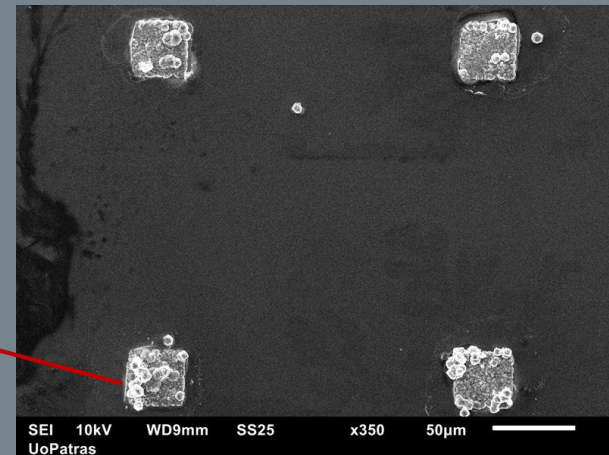
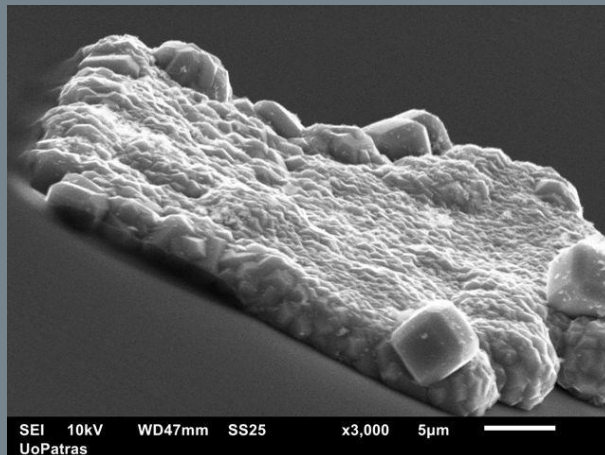
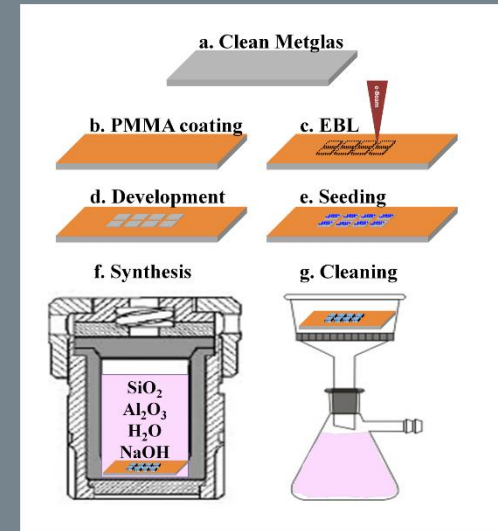
- Detection of six VOC's (o-xylene, p-xylene, n-hexane, c-hexane, benzene, ethyl-acetate)



- Development of two new techniques for stress measurement



- Development of a new technique for the fabrication of zeolite microfilms employing e-beam lithography
- Hydrothermal synthesis of Linde Type A (LTA) microfilm arrays of $20\mu\text{m}$ sides



Research Projects – All Groups Funding

Total Budget (2007-2013): 2.9 M€, 7 European Projects (65%), 4 National (25%), 4 Industrial (10%)

Characteristic Projects

- Joint Research and Technology Programs (Greece – Non-European countries), “Fabrication, characterization and testing of a nanostructured composite zeolite-metglas VOC/ odor sensor”, 2006-2008, 100k€
- INTERREG IIIA, GREECE – ITALY «Development of a multidisciplinary scientific network for the investigation and application of biomaterials” 2007 -2009, 650 k€
- UPAT – AIR LIQUIDE: " Catalytic Effect of Disilane Addition on $\mu\text{c-Si:H}$ growth rate ", Industrial Project, Air Liquide – Patras, 2011-2013, 100 k€
- EU FP7 "Demonstration of high performance Processes and equipment's for thin film silicon photovoltaic modules produced with lower environmental impact and reduced cost and material use", 2010-2013 850 k€
- THALIS, Title: " Design and fabrication of Robust super hydrophobic/hydrophilic surfaces and their application in the realization of “smart” microfluidic valves ", 2012-2015, 250 k€
- FP6-RII3, “European Integrated Activity of Excellence and Networking for Nano and Micro-Electronics Analysis”, 2006-2011 130 k€
- FP7- NoE/ICT, “Network of Excellence for building up knowledge for improved system integration for Flexible Organic and Large Area Electronics (FOLAE) and its exploitation”, 2010-2012, 170 k€

Total No of Publications SCI journals: ~114 (2007-2013), Citations (excluding self): ~2100

Conference Proceedings and Announcements: ~210 (2007-2013)

Few examples

1. A modified method for the calculation of the humidity adsorption stresses inside zeolite films using magnetoelastic sensors, T. Baimpos, V. Tsukala, V. Nikolakis, D. Kouzoudis, *Sens. Lett.* (2012), 10, 879
2. A new method for measuring the adsorption induced stresses of zeolite films using magnetoelastic sensors, T. Baimpos, D. Kouzoudis, V. Nikolakis, *J. of Membrane Science*, 390–391, 130–140, (2012)
3. “A hybrid kinetic Monte Carlo method for simulating silicon films grown by plasma-enhanced chemical vapor deposition” D.G. Tsalikis, C. Baig, V.G. Mavrantzas, E. Amanatides and D. Mataras *Journal of Chemical Physics*, Accepted Corrected Proofs (2013)
4. "Growth kinetics of plasma deposited microcrystalline silicon thin Flms", E. Amanatides and D. Mataras, *Surf. Coat. Technol.*, 205 178 (2011)
5. High performance OLEDs embedding tungsten suboxide as efficient hole injection layer” , M. Vasilopoulou, G. Papadimitropoulos, L. C. Palilis, D. G. Georgiadou, P.Argitis, S. Kennou, I. Kostis, N. Vourdas, N. A. Stathopoulos , D. Davazoglou, *Organic Electronics*, 13, 796 (2012).
6. “An X-ray photoelectron spectroscopy study of strontium-titanate-based high-k film stacks” , L.Sygellou, H. Tielens, C.Adelmann, S.Ladas, *Microelectronic Engineering*, 90, 138 (2012).
7. “Electronic and interface properties of polyfluorene films on GaN for hybrid optoelectronic applications” G. Itskos, X. Xristodoulou, E. Iliopoulos, S. Ladas, S. Kennou, M. Neophytou, S. Choulis, *Appl. Phys.Lett*, 102, 063303 (2013).

THANKS FOR THE ATTENTION

